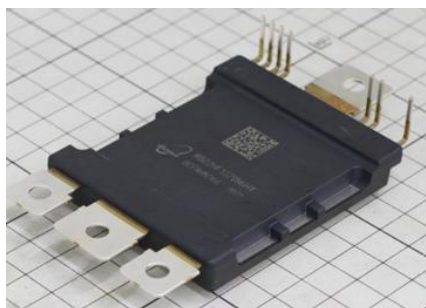
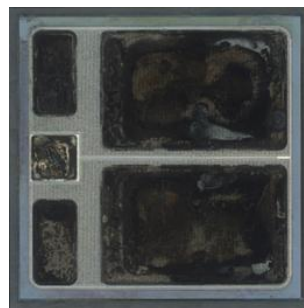


## SiC power Module (1200V) : StarPower MD22HFS120N6HY Module, SiC MOSFET Analysis Reports



Module



SiC MOSFET Die

### Report Overview

June 2024, Chinese company StarPower Semiconductor announced a SiC power module for 800V EV drive. This module features extremely low on-resistance using 1200V SiC MOSFETs, making it usable even in 800V onboard power supply environments.

Its molded, single-sided cooling structure, solid copper base plate with PINFIN structure, and AMB (Si<sub>3</sub>N<sub>4</sub>) substrate demonstrate the company's commitment to current trends and reliability.

This report clarifies the features of this product through an analysis of the module's structure, an overview of the SiC MOSFETs mounted, and a structural analysis.

### Product Features

Product type: MD22HFS120N6HY  $V_{DS} = 1200V$ 、 $I_D = 648A$ 、 $R_{DS(ON)} = 2.12m\Omega$   
Released data: June 2024

Datasheet : <https://www.powersemi.com/Upload/Products/202407//pdf/MD22HFS120N6HY.pdf>

- Half-bridge module 2 in 1-package
- Applications: Hybrid and electric vehicles, motor drive inverters

### Analysis result summary

#### ① Module Structure Analysis Report (44 pages)

- Cu pad is formed on the source bonding area of SiC MOSFET.
- Ag sinter is used to connect SiC MOSFET to AMB substrate and aforementioned pad.

#### ② SiC MOSFET Overview Analysis Report (15 pages)

- The  $R_{on}$  x AA of this product is comparable to STMicroelectronics' 3rd-generation SiC MOSFETs.

#### ③ SiC MOSFET Structure Analysis Report (53 pages)

- The gate oxide film is thinner than that of a typical planar SiC MOSFET.

### Report price

Delivered one week after order placement. Please contact us for report pricing.

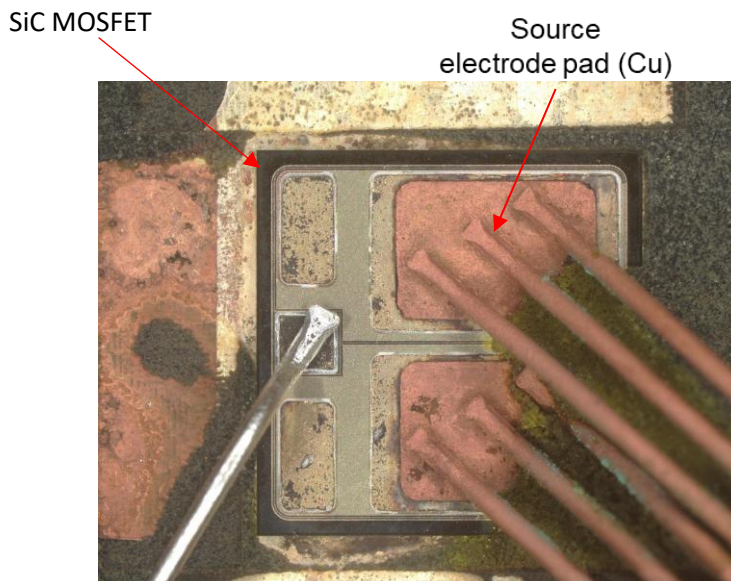
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## ① Excerpt from Module Structure Analysis Report



Module Cross-section OM image



Internal Module Observation

## ② SiC MOSFET Overview Analysis Report Table of Contents

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## ② Excerpt from SiC MOSFET Overview Analysis Report

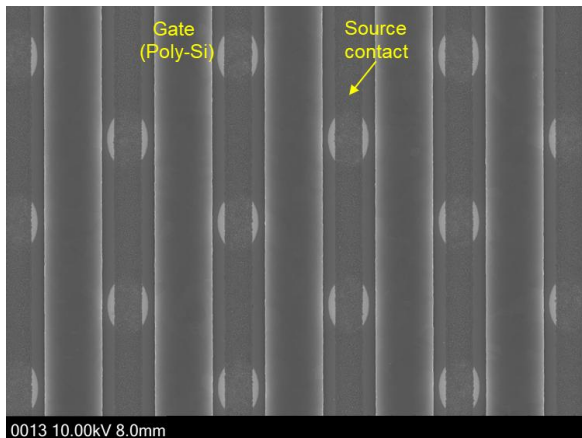
**Table : Device structure**

|  | StarPower<br>MD22HFS120N6HY | StarPower<br>DM400S12TDRB | Silan<br>SCDP120R013N2P4B | STMicro<br>SCT040W120G3AG |
|--|-----------------------------|---------------------------|---------------------------|---------------------------|
| Die size A<br>(mm x mm = mm <sup>2</sup> ) |                             |                           |                           |                           |
| Transistor area AA<br>(mm <sup>2</sup> )   |                             |                           |                           |                           |
| Ron<br>(mΩ / Vgs(V))                       |                             |                           |                           |                           |
| Ron x AA<br>(mΩ · mm <sup>2</sup> )        |                             |                           |                           |                           |
| Transistor cell<br>configuration           |                             |                           |                           |                           |
| Cell pitch P (μm)                          |                             |                           |                           |                           |
| Gate oxide film                            |                             |                           |                           |                           |

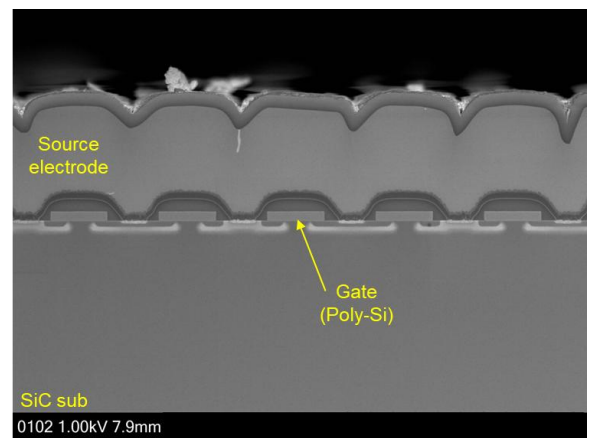
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### ③ Excerpt from SiC MOSFET Structure Analysis Report



Cell array plane SEM image (Poly-Si layer)



Cell array cross-section SEM image